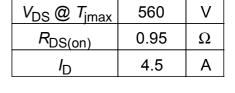


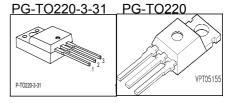
Cool MOS™ Power Transistor

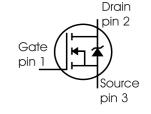
Feature

- New revolutionary high voltage technology
- Ultra low gate charge
- Periodic avalanche rated
- Extreme dv/dt rated
- Ultra low effective capacitances
- Improved transconductance
- PG-TO-220-3-31: Fully isolated package (2500 VAC; 1 minute)
- Pb-free lead plating; RoHS compliant
- Qualified according to JEDEC⁰⁾ for target applications

Туре	Package	Ordering Code	Marking
SPP04N50C3	PG-TO220	Q67040-S4575	04N50C3
SPA04N50C3	PG-TO220-3-31	SP000216298	04N50C3







Maximum Ratings

Parameter	Symbol	Va	Unit	
		SP	SPA	
Continuous drain current	I _D			Α
T _C = 25 °C		4.5	4.5 ¹⁾	
<i>T</i> _C = 100 °C		2.8	2.81)	
Pulsed drain current, t_p limited by T_{jmax}	I _{D puls}	13.5	13.5	Α
Avalanche energy, single pulse	E _{AS}	130	130	mJ
$I_{\rm D}$ =3.4A, $V_{\rm DD}$ =50V				
Avalanche energy, repetitive t_{AR} limited by T_{jmax}^{2}	E _{AR}	0.4	0.4	
I _D =4.5A, V _{DD} =50V				
Avalanche current, repetitive t_{AR} limited by T_{jmax}	I _{AR}	4.5	4.5	Α
Gate source voltage	V _{GS}	±20	±20	V
Gate source voltage AC (f >1Hz)	V_{GS}	±30	±30	
Power dissipation, $T_C = 25^{\circ}C$	P _{tot}	50	31	W
Operating and storage temperature	$T_{\rm j}$, $T_{\rm stg}$	-55	.+150	°C
Reverse diode dv/dt 7)	dv/dt	15		V/ns



Maximum Ratings

Parameter	Symbol	Value	Unit
Drain Source voltage slope	d <i>v</i> /d <i>t</i>	50	V/ns
$V_{\rm DS}$ = 400 V, $I_{\rm D}$ = 4.5 A, $T_{\rm j}$ = 125 °C			

Thermal Characteristics

Parameter	Symbol		Values		
		min.	typ.	max.	
Thermal resistance, junction - case	R _{thJC}	-	-	2.5	K/W
Thermal resistance, junction - case, FullPAK	R _{thJC FP}	-	-	4	
Thermal resistance, junction - ambient, leaded	R_{thJA}	-	-	62	
Thermal resistance, junction - ambient, FullPAK	R _{thJA_FP}	-	-	80	
SMD version, device on PCB:	R_{thJA}				
@ min. footprint		-	-	62	
@ 6 cm ² cooling area ³⁾		-	35	-	
Soldering temperature, wavesoldering	T _{sold}	-	-	260	°C
1.6 mm (0.063 in.) from case for 10s ⁴⁾					

Electrical Characteristics, at $T_{\rm j}$ =25°C unless otherwise specified

Parameter	Symbol	Conditions	Values			Unit
			min.	typ.	max.	
Drain-source breakdown voltage	V _{(BR)DSS}	V _{GS} =0V, I _D =0.25mA	500	-	-	V
Drain-Source avalanche breakdown voltage	V _{(BR)DS}	V _{GS} =0V, I _D =4.5A	-	600	-	
Gate threshold voltage	V _{GS(th)}	I_{D} =200 μ A, V_{GS} = V_{DS}	2.1	3	3.9	
Zero gate voltage drain current	I _{DSS}	V _{DS} =500V, V _{GS} =0V,				μA
		<i>T</i> _j =25°C	-	0.1	1	
		<i>T</i> _j =150°C	-	-	100	
Gate-source leakage current	I_{GSS}	V _{GS} =20V, V _{DS} =0V	-	-	100	nA
Drain-source on-state resistance	R _{DS(on)}	V _{GS} =10V, I _D =2.8A				Ω
		<i>T</i> _j =25°C	-	0.85	0.95	
		<i>T</i> _j =150°C	-	2.3	-	
Gate input resistance	R _G	f=1MHz, open drain	-	1.4	-	



Electrical Characteristics

Parameter	Symbol	Conditions		Values		Unit
			min.	typ.	max.	
Transconductance	<i>g</i> fs	V _{DS} ≥2*I _D *R _{DS(on)max} ,	-	4.4	-	S
		I _D =2.8A				
Input capacitance	C _{iss}	V _{GS} =0V, V _{DS} =25V,	-	470	-	pF
Output capacitance	Coss	f=1MHz	-	160	-	
Reverse transfer capacitance	C _{rss}		-	15	-	
Effective output capacitance,5)		V _{GS} =0V,	-	27	-	
energy related	, ,	V _{DS} =0V to 400V				
Effective output capacitance,6)	C _{o(tr)}		-	44	-	
time related						
Turn-on delay time	t _{d(on)}	V _{DD} =350V, V _{GS} =0/10V,	-	10	-	ns
Rise time	t _r	I _D =4.5A,	-	5	-	
Turn-off delay time	<i>t</i> _{d(off)}	R_{G} =18 Ω	-	70	-	
Fall time	t _f		-	10	-	

Gate Charge Characteristics

Gate to source charge	Q_{gs}	V _{DD} =400V, I _D =4.5A	-	2.2	-	nC
Gate to drain charge	Q_{gd}		ı	10	-	
Gate charge total	Qg	V _{DD} =400V, I _D =4.5A,	-	22	-	
		V _{GS} =0 to 10V				
Gate plateau voltage	V _(plateau)	V _{DD} =400V, I _D =4.5A	_	5	-	V

⁰J-STD20 and JESD22

¹Limited only by maximum temperature

²Repetitve avalanche causes additional power losses that can be calculated as $P_{AV} = E_{AR} * f$.

 $^{^3}$ Device on 40mm*40mm*1.5mm epoxy PCB FR4 with 6cm² (one layer, 70 μ m thick) copper area for drain connection. PCB is vertical without blown air.

⁴Soldering temperature for TO-263: 220°C, reflow

 $^{^5}C_{
m o(er)}$ is a fixed capacitance that gives the same stored energy as $C_{
m oss}$ while $V_{
m DS}$ is rising from 0 to 80% $V_{
m DSS}$.

 $^{^6}C_{\rm o(tr)}$ is a fixed capacitance that gives the same charging time as $C_{\rm oss}$ while $V_{\rm DS}$ is rising from 0 to 80% $V_{\rm DSS}$.

 $^{^{7}}I_{SD}$ <= I_{D} , di/dt<=400A/us, V_{DClink} =400V, V_{peak} < $V_{BR, DSS}$, T_{j} < $T_{j,max}$. Identical low-side and high-side switch.

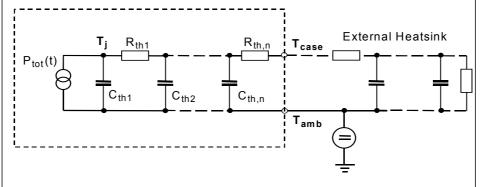


Electrical Characteristics

Parameter	Symbol	Conditions	Values			Unit
			min.	typ.	max.	
Inverse diode continuous	IS	<i>T</i> _C =25°C	-	-	4.5	Α
forward current						
Inverse diode direct current,	/ _{SM}		-	-	13.5	
pulsed						
Inverse diode forward voltage	V _{SD}	V _{GS} =0V, I _F =I _S	-	1	1.2	V
Reverse recovery time	t _{rr}	V_{R} =400V, I_{F} = I_{S} ,	-	280	-	ns
Reverse recovery charge	Q _{rr}	d <i>i</i> _F /d <i>t</i> =100A/μs	-	2.3	-	μC
Peak reverse recovery current	/ _{rrm}		-	16	-	Α
Peak rate of fall of reverse	di _{rr} /dt	<i>T</i> _j =25°C	-	860	-	A/µs
recovery current						

Typical Transient Thermal Characteristics

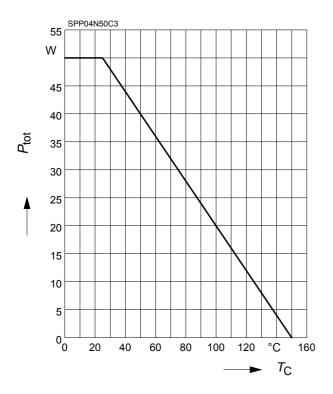
Symbol	Va	lue	Unit	Symbol	Value		Unit
	SPP_B	SPA			SPP_B	SPA	
R _{th1}	0.039	0.039	K/W	C _{th1}	0.00007347	0.00007347	Ws/K
R _{th2}	0.074	0.074		C _{th2}	0.0002831	0.0002831	
R _{th3}	0.132	0.132		C _{th3}	0.0004062	0.0004062	
R _{th4}	0.555	0.272		C _{th4}	0.001215	0.001215	
R _{th5}	0.529	0.559		C _{th5}	0.00276	0.005633	
R _{th6}	0.169	2.523		C _{th6}	0.029	0.412	





1 Power dissipation

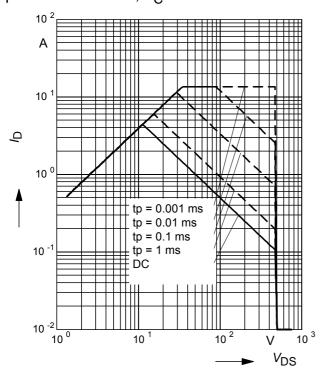
$$P_{\text{tot}} = f(T_{\text{C}})$$



3 Safe operating area

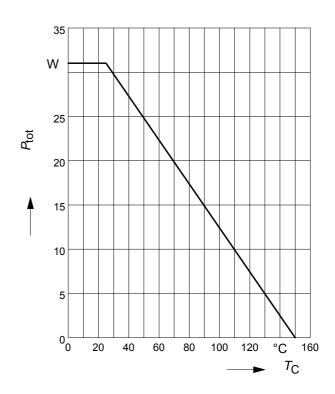
$$I_{D} = f(V_{DS})$$

parameter : D = 0 , $T_C = 25^{\circ}C$



2 Power dissipation FullPAK

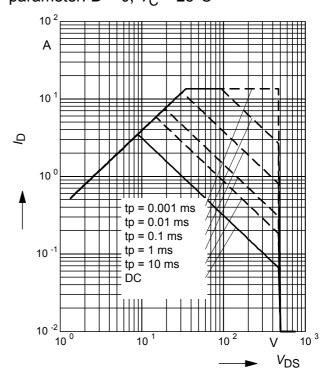
$$P_{\text{tot}} = f(T_{\text{C}})$$



4 Safe operating area FullPAK

$$I_{\rm D} = f(V_{\rm DS})$$

parameter: D = 0, $T_C = 25$ °C

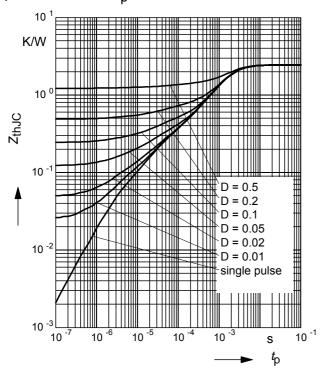




5 Transient thermal impedance

$$Z_{\text{thJC}} = f(t_{\text{p}})$$

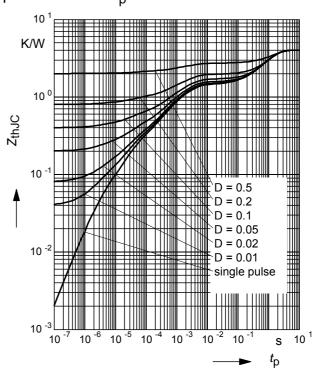
parameter: $D = t_D/T$



6 Transient thermal impedance FullPAK

$$Z_{\text{thJC}} = f(t_{\text{p}})$$

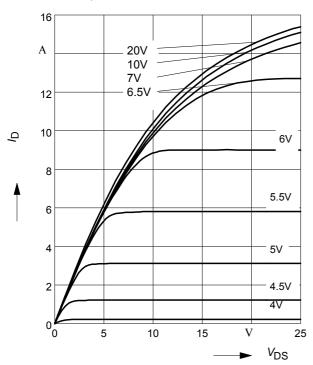
parameter: $D = t_D/t$



7 Typ. output characteristic

 $I_{D} = f(V_{DS}); T_{i}=25^{\circ}C$

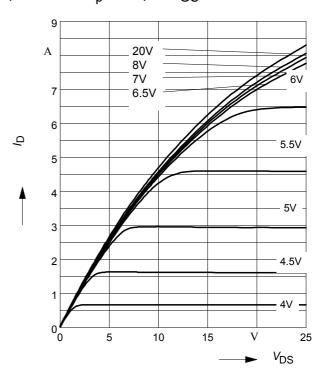
parameter: t_p = 10 μ s, V_{GS}



8 Typ. output characteristic

 $I_{D} = f(V_{DS}); T_{j}=150^{\circ}C$

parameter: $t_p = 10 \mu s$, V_{GS}

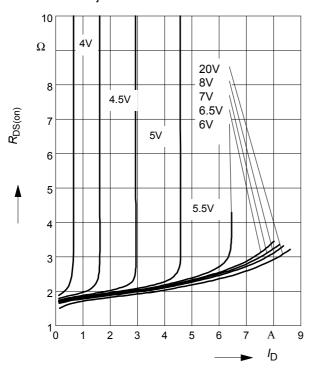




9 Typ. drain-source on resistance

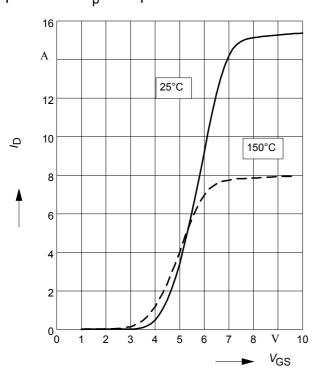
 $R_{DS(on)} = f(I_D)$

parameter: T_i =150°C, V_{GS}



11 Typ. transfer characteristics

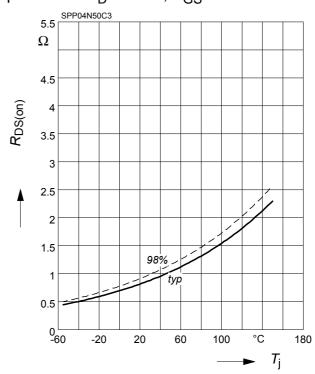
 $I_{\rm D}$ = f ($V_{\rm GS}$); $V_{\rm DS}$ \geq 2 x $I_{\rm D}$ x $R_{\rm DS(on)max}$ parameter: $t_{\rm p}$ = 10 $\mu {\rm s}$



10 Drain-source on-state resistance

 $R_{\mathsf{DS}(\mathsf{on})} = f(T_{\mathsf{j}})$

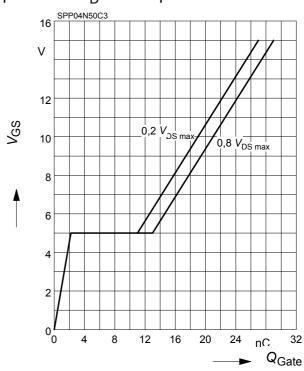
parameter : I_D = 2.8 A, V_{GS} = 10 V



12 Typ. gate charge

 $V_{GS} = f (Q_{Gate})$

parameter: I_D = 4.5 A pulsed

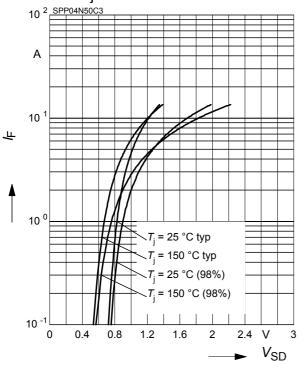




13 Forward characteristics of body diode

$$I_{\mathsf{F}} = f(\mathsf{V}_{\mathsf{SD}})$$

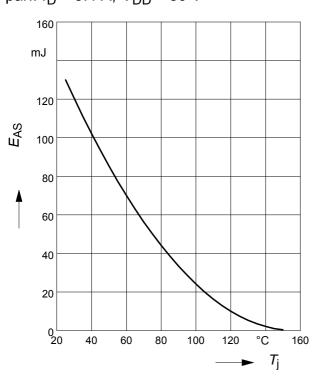
parameter: T_i , $t_p = 10 \mu s$



15 Avalanche energy

$$E_{AS} = f(T_i)$$

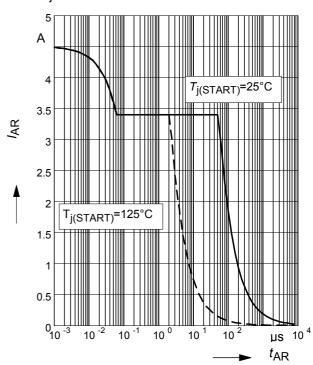
par.: $I_D = 3.4 \text{ A}, V_{DD} = 50 \text{ V}$



14 Avalanche SOA

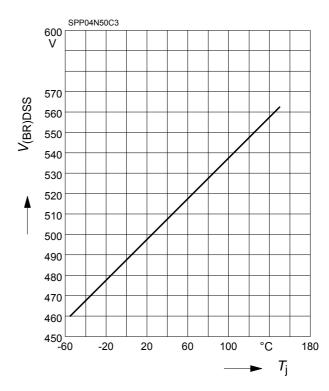
$$I_{AR} = f(t_{AR})$$

par.: $T_j \le 150 \, ^{\circ}\text{C}$



16 Drain-source breakdown voltage

$$V_{(BR)DSS} = f(T_j)$$

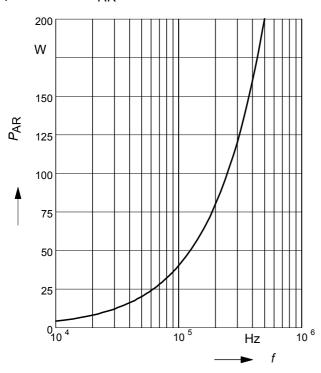




17 Avalanche power losses

 $P_{AR} = f(f)$

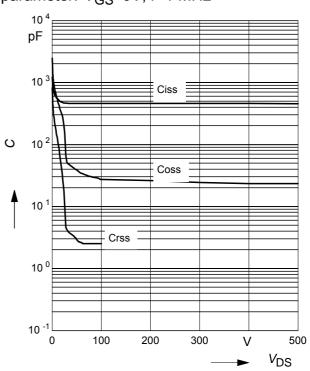
parameter: E_{AR}=0.4mJ



18 Typ. capacitances

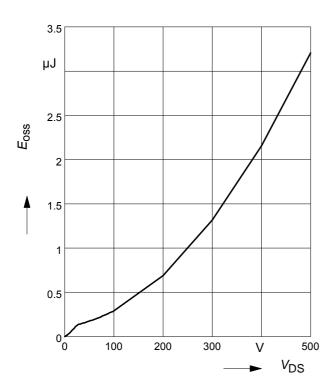
 $C = f(V_{DS})$

parameter: V_{GS} =0V, f=1 MHz



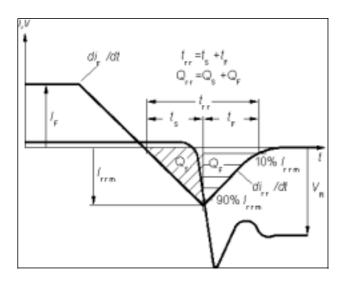
19 Typ. $C_{\rm OSS}$ stored energy

 $E_{\text{oss}} = f(V_{\text{DS}})$



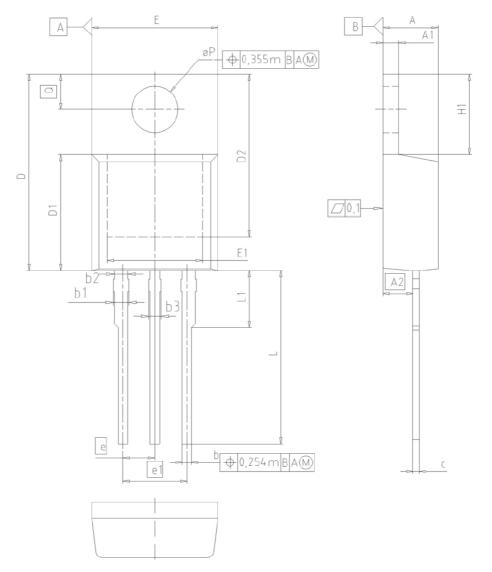


Definition of diodes switching characteristics

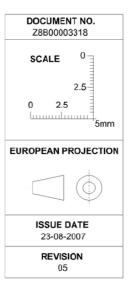




PG-TO220-3-1, PG-TO220-3-21

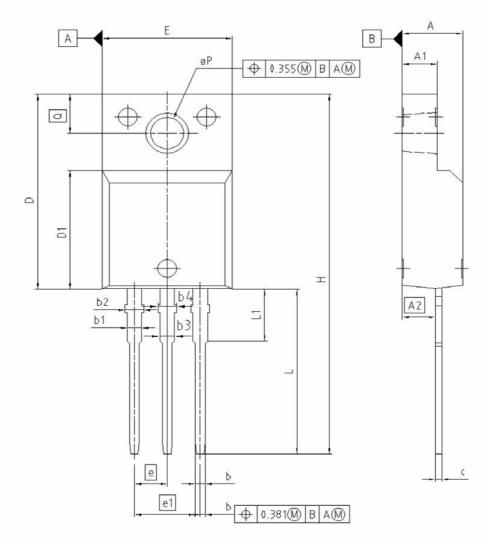


DIM	MILLIM	IETERS	INC	HES
DIM	MIN	MAX	MIN	MAX
Α	4.30	4.57	0.169	0.180
A1	1.17	1.40	0.046	0.055
A2	2.15	2.72	0.085	0.107
b	0.65	0.86	0.026	0.034
b1	0.95	1.40	0.037	0.055
b2	0.95	1.15	0.037	0.045
b3	0.65	1.15	0.026	0.045
С	0.33	0.60	0.013	0.024
D	14.81	15.95	0.583	0.628
D1	8.51	9.45	0.335	0.372
D2	12.19	13.10	0.480	0.516
E	9.70	10.36	0.382	0.408
E1	6.50	8.60	0.256	0.339
е	2.5	54	0.1	00
e1	5.0	08	0.2	200
N		3	;	3
H1	5.90	6.90	0.232	0.272
L	13.00	14.00	0.512	0.551
L1	-	4.80	-	0.189
øΡ	3.60	3.89	0.142	0.153
Q	2.60	3.00	0.102	0.118





PG-TO220-3-31 (FullPAK)



DIM	MILLIN	METERS	INC	HES
DIM	MIN	MAX	MIN	MAX
Α	4.55	4.85	0.179	0.191
A1	2.55	2.85	0.100	0.112
A2	2.42	2.72	0.095	0.107
b	0.65	0.85	0.026	0.033
b1	0.95	1.33	0.037	0.052
b2	0.95	1.51	0.037	0.059
b3	0.65	1.33	0.026	0.052
b4	0.65	1.51	0.026	0.059
С	0.40	0.63	0.016	0.025
D	15.85	16.15	0.624	0.636
D1	9.53	9.83	0.375	0.387
E	10.35	10.65	0.407	0.419
e	2.	.54	0.1	100
e1	5.	80	0.2	200
N		3	3	
Н	29.45	29.75	1.159	1.171
L	13.45	13.75	0.530	0.541
L1	3.15	3.45	0.124	0.136
øΡ	2.95	3.20	0.116	0.126
Q	3.15	3.50	0.124	0.138

REFERENCE
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18SUE DATE 08-01-2007
FILE TO220_2



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